

Features

- Uses CRM(CQ) advanced SkyMOS1 technology
- Extremely low on-resistance $R_{DS(on)}$
- Excellent $Q_g \times R_{DS(on)}$ product(FOM)
- Qualified according to JEDEC criteria

Product Summary

V_{DS}	100V
$R_{DS(on)}$	3.3mΩ
I_D	180A

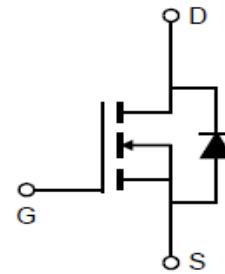
Applications

- Motor control and drive
- Battery management
- UPS (Uninterruptible Power Supplies)

100% Avalanche Tested



CRSQ036N10N



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRSQ036N10N	-	TO-247	Tube	N/A	N/A	30pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	100	V
Continuous drain current $T_C = 25^\circ\text{C}$ (Silicon limit) $T_C = 25^\circ\text{C}$ (Package limit) $T_C = 100^\circ\text{C}$ (Silicon limit)	I_D	240 180 155	A
Pulsed drain current ($T_C = 25^\circ\text{C}$, t_p limited by $T_{j,\max}$)	$I_{D\text{ pulse}}$	720	A
Avalanche energy, single pulse ($L=0.5\text{mH}$, $R_g=25\Omega$) ^[1]	E_{AS}	342	mJ
Gate-Source voltage	V_{GS}	± 20	V
Power dissipation ($T_C = 25^\circ\text{C}$)	P_{tot}	454	W
Operating junction and storage temperature	T_j , T_{stg}	-55...+150	°C

Notes: 1. EAS was tested at $T_j = 25^\circ\text{C}$, $I_D = 37\text{A}$.

Thermal Resistance

Parameter		Symbol	Max	Unit
Thermal resistance, junction - case.		R _{thJC}	0.28	°C/W
Thermal resistance, junction - ambient(min. footprint)		R _{thJA}	48	

Electrical Characteristic (at T_j = 25 °C, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	BV _{DSS}	100	-	-	V	V _{GS} =0V, I _D =250μA
Gate threshold voltage	V _{GS(th)}	2.2	3	3.8	V	V _{DS} =V _{GS} , I _D =250μA
Zero gate voltage drain current	I _{DSS}	-	0.05	1	μA	V _{DS} =80V, V _{GS} =0V T _j =25°C T _j =125°C
Gate-source leakage current	I _{GSS}	-	-	±100	nA	V _{GS} =±20V, V _{DS} =0V
Drain-source on-state resistance	R _{DS(on)}	-	3.3	4.0	mΩ	V _{GS} =10V, I _D =90A
Transconductance	g _f	-	175	-	S	V _{DS} =5V, I _D =90A

Dynamic Characteristic

Input Capacitance	C _{iss}	-	7505	-	pF	V _{GS} =0V, V _{DS} =50V, f=1MHz
Output Capacitance	C _{oss}	-	776	-		
Reverse Transfer Capacitance	C _{rss}	-	28	-		
Gate Total Charge	Q _G	-	127	-	nC	V _{GS} =10V, V _{DS} =50V, I _D =90A, f=1MHz
Gate-Source charge	Q _{gs}	-	46	-		
Gate-Drain charge	Q _{gd}	-	36	-		
Turn-on delay time	t _{d(on)}	-	30	-	ns	V _{GS} =10V, V _{DD} =50V, R _{G_ext} =3.0Ω
Rise time	t _r	-	109	-		
Turn-off delay time	t _{d(off)}	-	64	-		
Fall time	t _f	-	115	-		
Gate resistance	R _G	-	1.9	-	Ω	V _{GS} =0V, V _{DS} =0V, f=1MHz

Body Diode Characteristic


Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V _{SD}	-	0.94	1.4	V	V _{GS} =0V, I _{SD} =90A
Body Diode Reverse Recovery Time	t _{rr}	-	91	-	ns	I _F =90A, dI/dt=100A/μs
Body Diode Reverse Recovery Charge	Q _{rr}	-	269	-	nC	

Typical Performance Characteristics

Fig 1: Output Characteristics

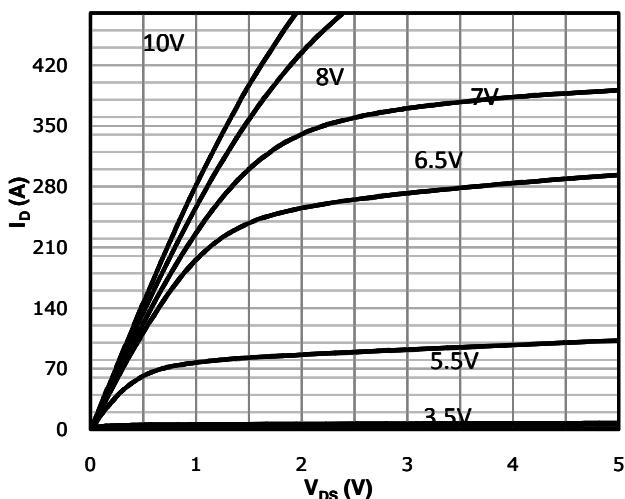


Fig 2: Transfer Characteristics

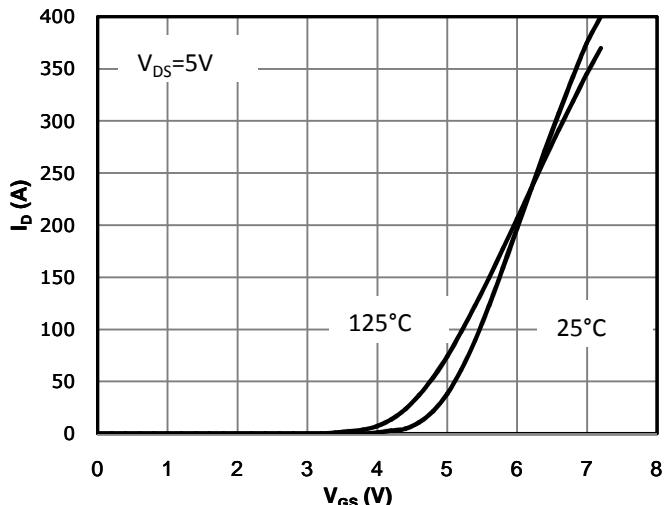


Fig 3: $R_{DS(on)}$ vs Drain Current and Gate Voltage

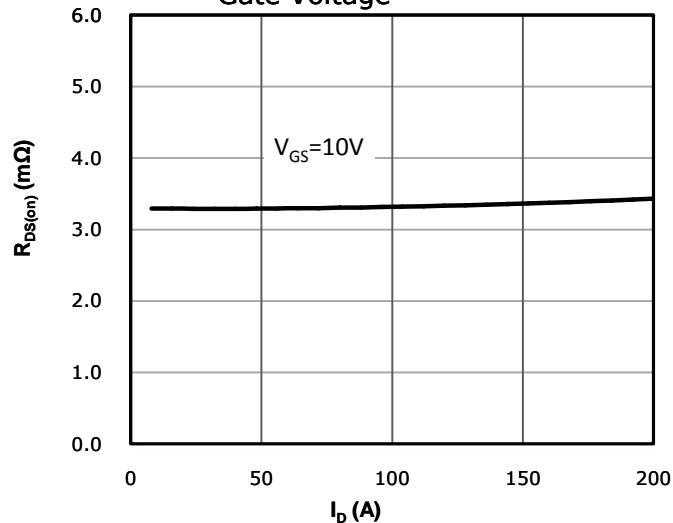


Fig 5: $R_{DS(on)}$ vs. Temperature

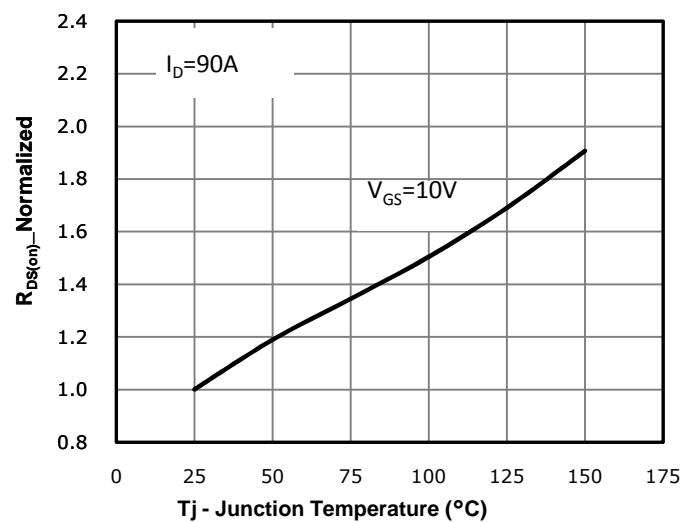


Fig 4: $R_{DS(on)}$ vs Gate Voltage

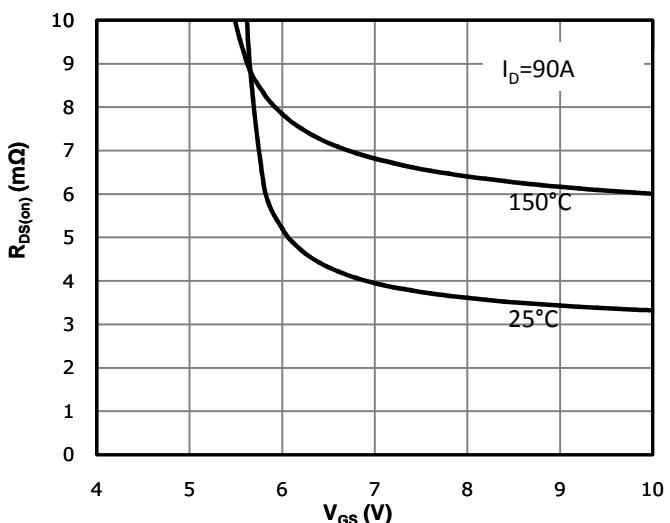


Fig 6: Capacitance Characteristics

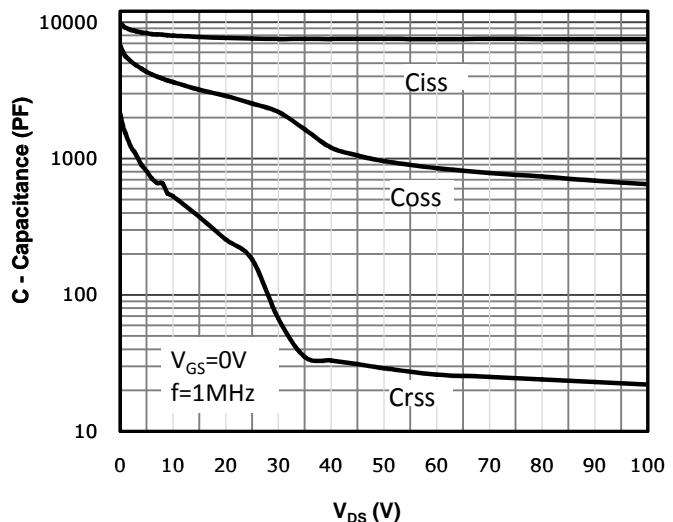


Fig 7: Gate Charge Characteristics

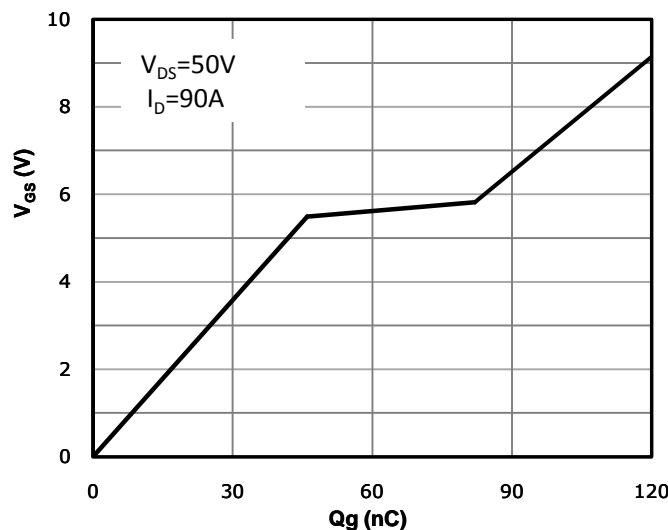


Fig 8: Body-diode Forward Characteristics

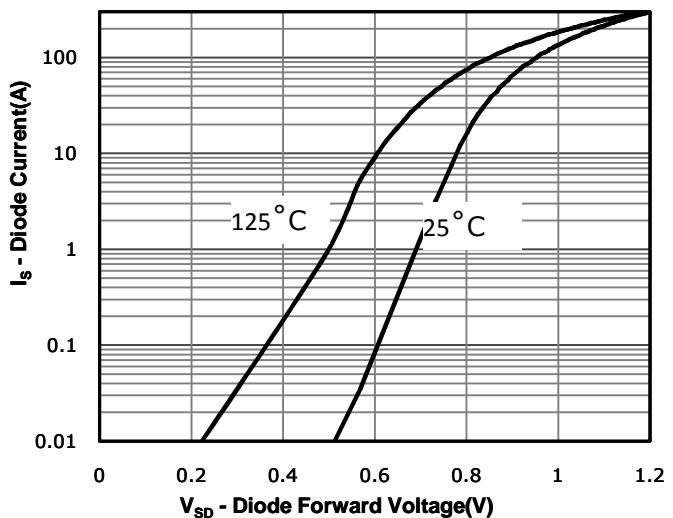


Fig 9: Power Dissipation

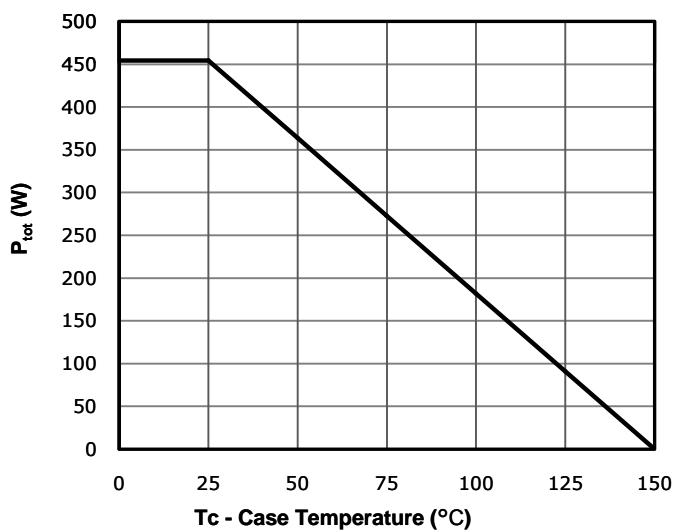


Fig 10: Drain Current Derating

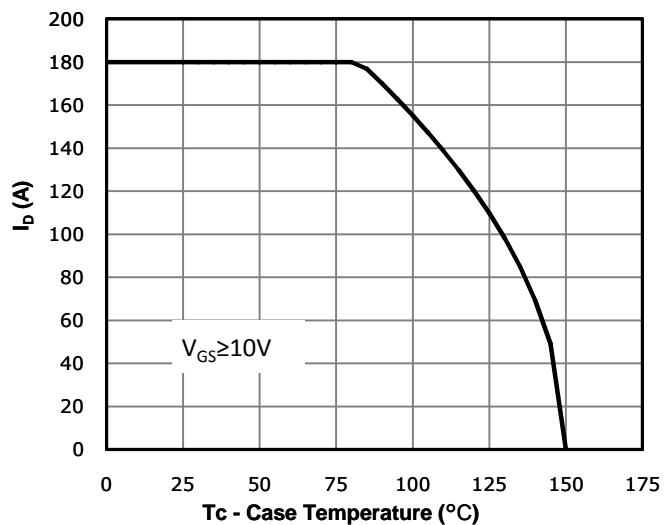


Fig 11: Safe Operating Area

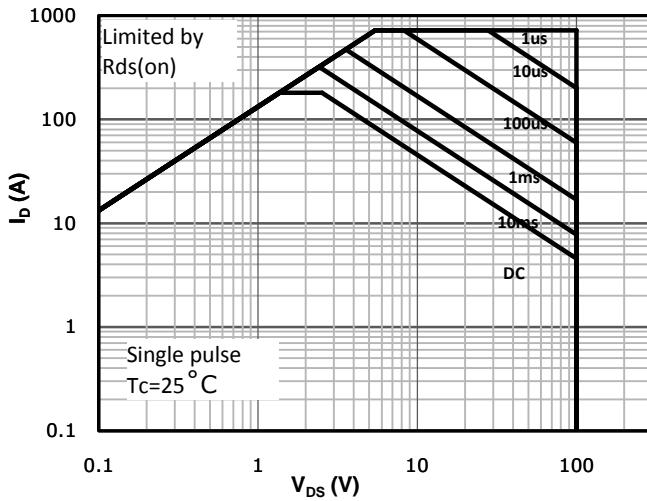
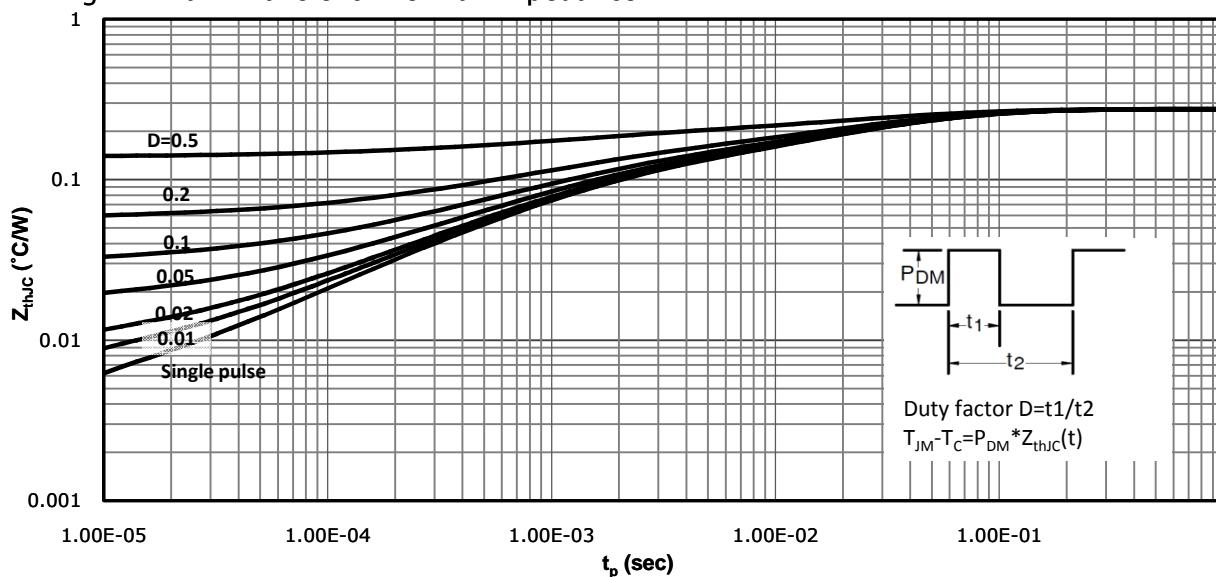
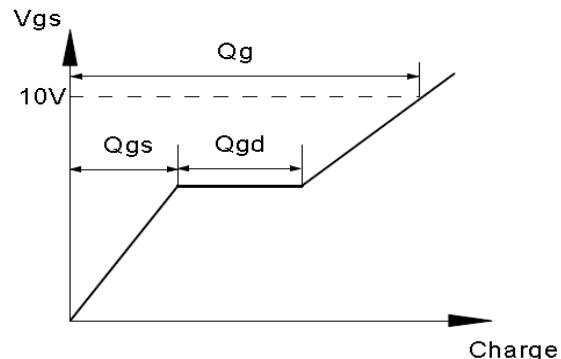
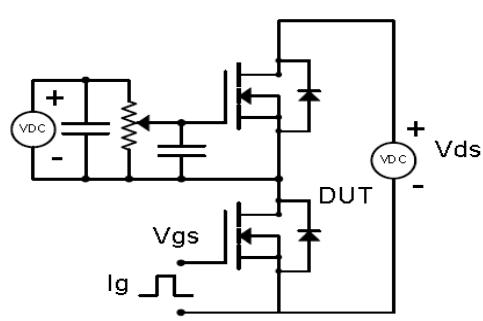


Fig 12: Max. Transient Thermal Impedance

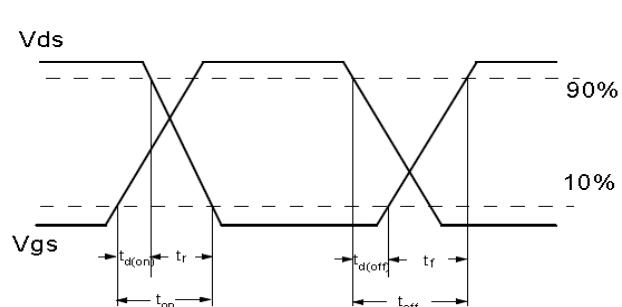
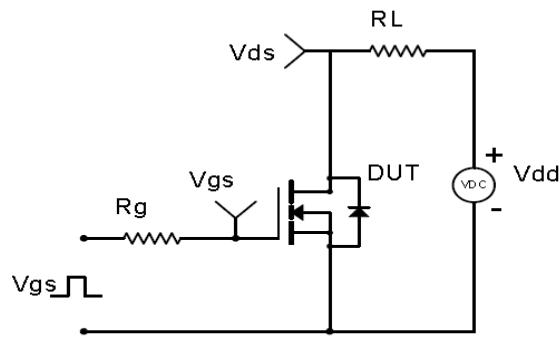


Test Circuit & Waveform

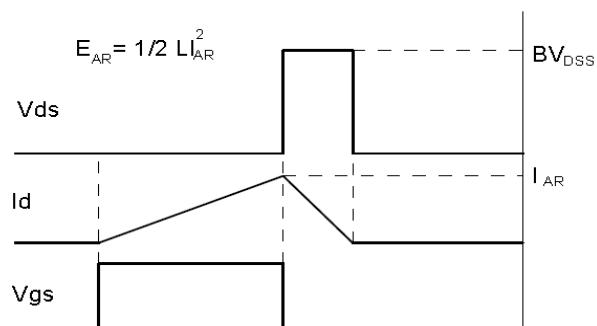
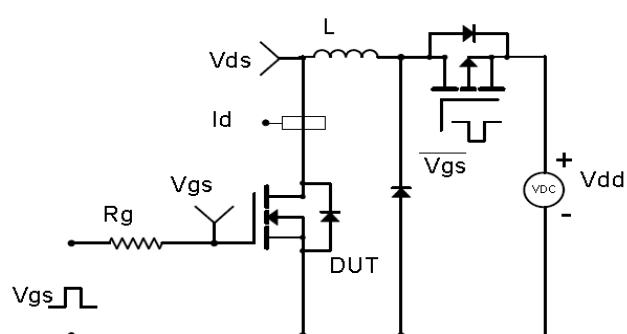
Gate Charge Test Circuit & Waveform



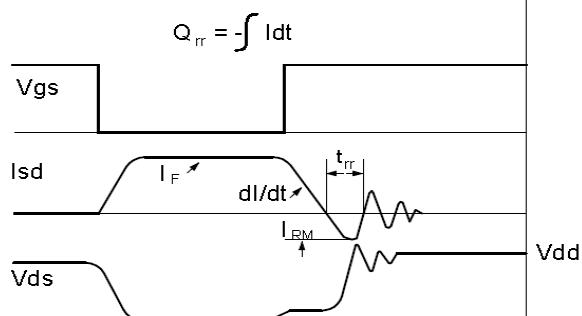
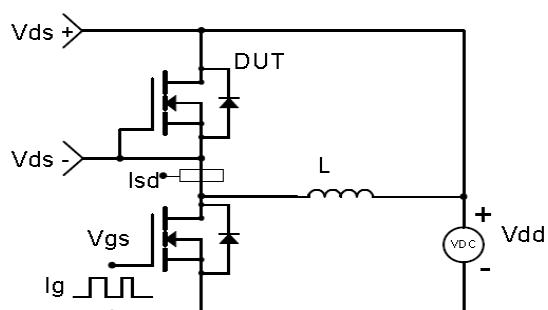
Resistive Switching Test Circuit & Waveforms

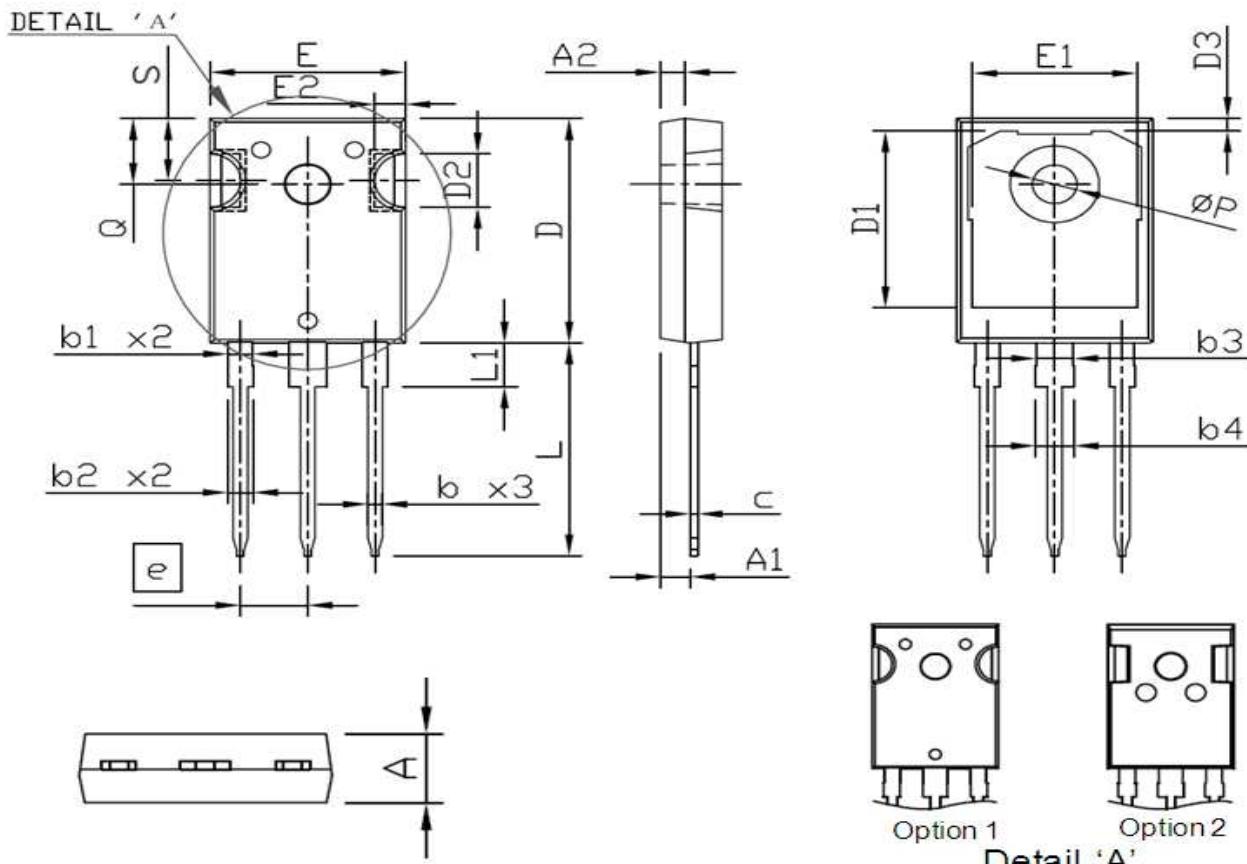


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Outline: TO-247


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.85	5.15	0.191	0.203
A1	2.27	2.54	0.089	0.100
A2	1.90	2.10	0.075	0.083
b	1.07	1.33	0.042	0.052
b1	1.90	2.16	0.075	0.085
b2	2.00	2.21	0.079	0.087
b3	2.87	3.13	0.113	0.123
b4	2.87	3.20	0.113	0.126
c	0.55	0.68	0.022	0.027
D	20.80	21.10	0.819	0.831
D1	16.25	17.65	0.640	0.695
D2	3.68	5.10	0.145	0.201
D3	0.95	1.35	0.037	0.053
e	5.44 BSC.		0.214 BSC.	
E	15.70	16.13	0.618	0.635
E1	13.03	14.15	0.513	0.557
E2	2.20	2.60	0.087	0.102
L	19.72	20.32	0.776	0.800
L1	4.00	4.47	0.157	0.176
Q	6.04	6.30	0.238	0.248
P	3.50	3.70	0.138	0.146
S	5.49	6.00	0.216	0.236

Revision History

Revison	Date	Major changes
1.0	2020-01-06	Release of formal version.

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM(CQ) reserves the right to improve product design, function and reliability without notice.